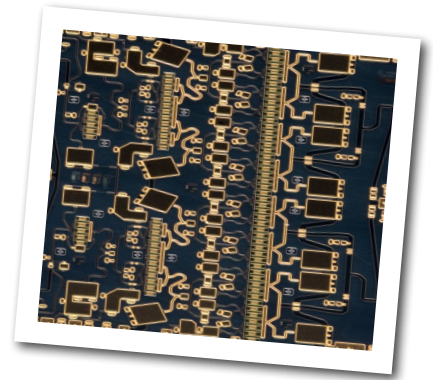


# CPMA601C025D

## 25 W, 6.0 - 12.0 GHz, GaN MMIC, Power Amplifier



Cree's CPMA601C025D is a gallium nitride (GaN) High Electron Mobility Transistor (HEMT) based monolithic microwave integrated circuit (MMIC) on a silicon carbide substrate, using a 0.25  $\mu\text{m}$  gate length fabrication process. GaN-on-SiC has superior properties compared to silicon, gallium arsenide or GaN-on-Si, including higher breakdown voltage, higher saturated electron drift velocity and higher thermal conductivity. GaN HEMTs also offer greater power density and wider bandwidths compared to Si, GaAs, and GaN-on-Si transistors. This MMIC contains a reactively matched amplifier design approach enabling very wide bandwidths to be achieved.

### Typical Performance Over 6.0-12.0 GHz ( $T_c = 25^\circ\text{C}$ )

Parameter	6.0 GHz	8.0 GHz	10.0 GHz	12.0 GHz	Units
Small Signal Gain	40.0	42.0	43.0	36.0	dB
$P_{\text{OUT}} @ P_{\text{IN}} = 19 \text{ dBm}$	48.0	49.0	47.4	47.3	dBm
$P_{\text{OUT}} @ P_{\text{IN}} = 19 \text{ dBm}$	63.0	79.0	55.0	54.0	W
Power Gain @ $P_{\text{IN}} = 19 \text{ dBm}$	29.0	30.0	28.4	27.3	dB
PAE @ $P_{\text{IN}} = 19 \text{ dBm}$	33.0	49.0	35.0	32.0	%

**Note: All data pulse tested on-wafer with Pulse Width = 10  $\mu\text{s}$ , Duty Cycle = 0.1%.**

### Features

- 32 dB Small Signal Gain
- 30 W Typical  $P_{\text{SAT}}$
- Operation up to 28 V
- High Breakdown Voltage
- High Temperature Operation
- Size 0.172 x 0.239 x 0.004 inches

### Applications

- Jamming Amplifiers
- Test Equipment Amplifiers
- Broadband Amplifiers
- Radar Amplifiers

## Absolute Maximum Ratings (not simultaneous) at 25 °C

Parameter	Symbol	Rating	Units	Conditions
Drain-source Voltage	$V_{DSS}$	84	$V_{DC}$	25 °C
Gate-source Voltage	$V_{GS}$	-10, +2	$V_{DC}$	25 °C
Storage Temperature	$T_{STG}$	-55, +150	°C	
Operating Junction Temperature	$T_J$	225	°C	
Maximum Forward Gate Current	$I_{GMAX}$	15	mA	25 °C
Maximum Drain Current <sup>1</sup>	$I_{DMAX}$	0.6	A	Stage 1, 25 °C
Maximum Drain Current <sup>1</sup>	$I_{DMAX}$	1.7	A	Stage 2, 25 °C
Maximum Drain Current <sup>1</sup>	$I_{DMAX}$	4.8	A	Stage 3, 25 °C
Thermal Resistance, Junction to Case (packaged)	$R_{\theta JC}$	0.83	°C/W	85 °C, $P_{DISS} = 92.8$ W in 440213 package
Thermal Resistance, Junction to Case (die only) <sup>2</sup>	$R_{\theta JC}$	0.36	°C/W	85 °C, $P_{DISS} = 92.8$ W
Mounting Temperature (30 seconds)	$T_S$	320	°C	30 seconds

Note<sup>1</sup> Current limit for long term, reliable operation

Note<sup>2</sup> Eutectic die attach using 80/20 AuSn mounted to a 10mil thick CuMo carrier.

## Electrical Characteristics (Frequency = 6.0 GHz to 12.0 GHz unless otherwise stated; $T_c = 25 °C$ )

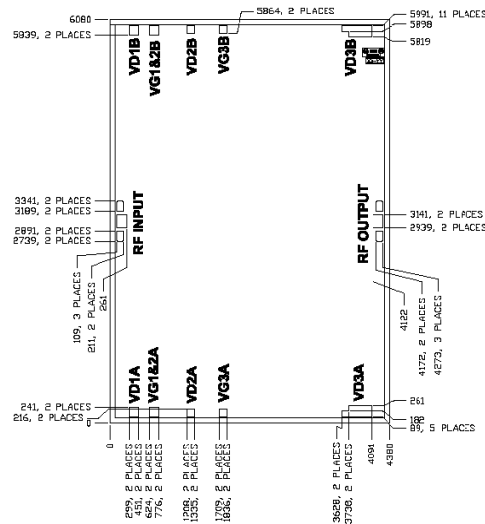
Characteristics	Symbol	Min.	Typ.	Max.	Units	Conditions
<b>DC Characteristics</b>						
Gate Threshold	$V_{TH}$	-3.8	-2.8	-2.3	V	$V_{DS} = 10$ V, $I_D = 23.2$ mA
Drain-Source Breakdown Voltage	$V_{BD}$	84	100	-	V	$V_{GS} = -8$ V, $I_D = 23.2$ mA
<b>RF Characteristics<sup>2</sup></b>						
Small Signal Gain @ 6 GHz	S21	29.8	35	-	dB	$V_{DD} = 28$ V, $I_{DQ} = 2.4$ A, $P_{IN} = 10$ dBm
Small Signal Gain @ 10 GHz	S21	30.2	35	-	dB	$V_{DD} = 28$ V, $I_{DQ} = 2.4$ A, $P_{IN} = 10$ dBm
Small Signal Gain @ 12 GHz	S21	27.8	35	-	dB	$V_{DD} = 28$ V, $I_{DQ} = 2.4$ A, $P_{IN} = 10$ dBm
Power Output	$P_{OUT}$	45.5	47	-	W	$V_{DD} = 28$ V, $I_{DQ} = 2.4$ A, $P_{IN} = 19$ dBm, Frequency = 6.0, 10.0, 12.0 GHz
Power Added Efficiency @ 6 GHz	PAE	23.0	30	-	%	$V_{DD} = 28$ V, $I_{DQ} = 2.4$ A, $P_{IN} = 19$ dBm
Power Added Efficiency @ 10 GHz	PAE	23.3	32	-	%	$V_{DD} = 28$ V, $I_{DQ} = 2.4$ A, $P_{IN} = 19$ dBm
Power Added Efficiency @ 12 GHz	PAE	23.7	31	-	%	$V_{DD} = 28$ V, $I_{DQ} = 2.4$ A, $P_{IN} = 19$ dBm
Power Gain	$G_p$	-	28	-	dB	$V_{DD} = 28$ V, $I_{DQ} = 2.4$ A, $P_{IN} = 19$ dBm
Input Return Loss	S11	-	-10	-	dB	$V_{DD} = 28$ V, $I_{DQ} = 2.4$ A
Output Return Loss	S22	-	-8	-	dB	$V_{DD} = 28$ V, $I_{DQ} = 2.4$ A
Output Mismatch Stress	VSWR	-	5 : 1	-	$\Psi$	No damage at all phase angles, $V_{DD} = 28$ V, $I_{DQ} = 2.4$ A, $P_{OUT} = 25$ W CW

Notes:

<sup>1</sup> Scaled from PCM data.

<sup>2</sup> All data pulse tested on-wafer with Pulse Width = 10  $\mu$ s, Duty Cycle = 0.1%.

## Die Dimensions (units in microns)



Overall die size 4380 x 6080 (+0/-50) microns, die thickness 100 (+/-10) microns.  
All Gate and Drain pads must be wire bonded for electrical connection.

Pad Number	Function	Description	Pad Size (in)	Note
1	RF IN	RF-Input pad. Matched to 50 ohm. The DC impedance ~ 0 ohm due matching circuit.	150 x 200	4
2	VD1_A	Drain supply for stage 1A. VD = 28 V.	150 x 150	1
3	VD1_B	Drain supply for stage 1B. VD = 28 V.	150 x 150	1
4	VG1&2_A	Gate control for stage 1&2A. VG = -2.0 to - 3.5 V.	150 x 150	1,2
5	VG1&2_B	Gate control for stage 1&2B. VG = -2.0 to - 3.5 V.	150 x 150	1,2
6	VD2_A	Drain supply for stage 2A. VD = 28 V.	129 x 129	1
7	VD2_B	Drain supply for stage 2B. VD = 28 V.	129 x 129	1
8	VG3_A	Gate control for stage 3A. VG = -2.0 to - 3.5 V.	129 x 129	1,3
9	VG3_B	Gate control for stage 3B. VG = -2.0 to - 3.5 V.	129 x 129	1,3
10	VD3_A	Drain supply for stage 3A. VD = 28 V.	-	1
11	VD3_B	Drain supply for stage 3B. VD = 28 V.	-	1
12	RF-OUT	RF-Output pad. Matched to 50 ohm.	150 x 200	4

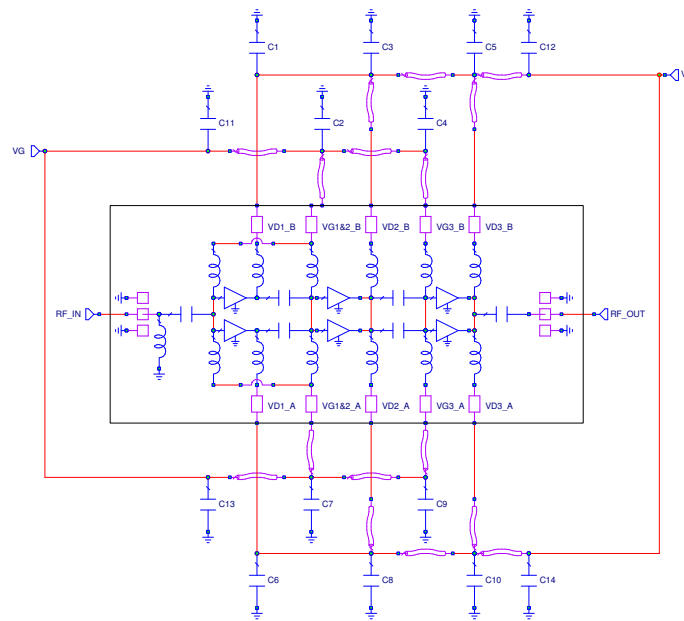
### Notes:

- Attach bypass capacitor to pads 2-11 per application circuit.
- VG1&2\_A and VG1&2\_B are connected internally so it would be enough to connect either one for proper operation.
- VG3\_A and VG3\_B are connected internally so it would be enough to connect either one for proper operation.
- The RF Input and Output pad have a ground-signal-ground with a nominal pitch of 10 mil (250 um). The RF ground pads are 100 x 100 microns.

### Die Assembly Notes:

- Recommended solder is AuSn (80/20) solder. Refer to Cree's website for the Eutectic Die Bond Procedure application note at <http://www.cree.com/~media/Files/Cree/RF/Application%20Notes/Appnote%202%20Eutectic.pdf>
- Vacuum collet is the preferred method of pick-up.
- The backside of the die is the Source (ground) contact.
- Die back side gold plating is 5 microns thick minimum.
- Thermosonic ball or wedge bonding are the preferred connection methods.
- Gold wire must be used for connections.
- Use the die label (XX-YY) for correct orientation.

## Block Diagram Showing Additional Capacitors for Operation Over 6.0 to 12.0 GHz



Designator	Description	Quantity
C1,C2,C3,C4,C5,C6,C7,C8,C9,C10	CAP, 51pF, +/-10%, SINGLE LAYER, 0.030", Er 3300, 100V, Ni/Au TERMINATION	10
C11,C12,C13,C14	CAP, 680pF, +/-10%, SINGLE LAYER, 0.070", Er 3300, 100V, Ni/Au TERMINATION	4

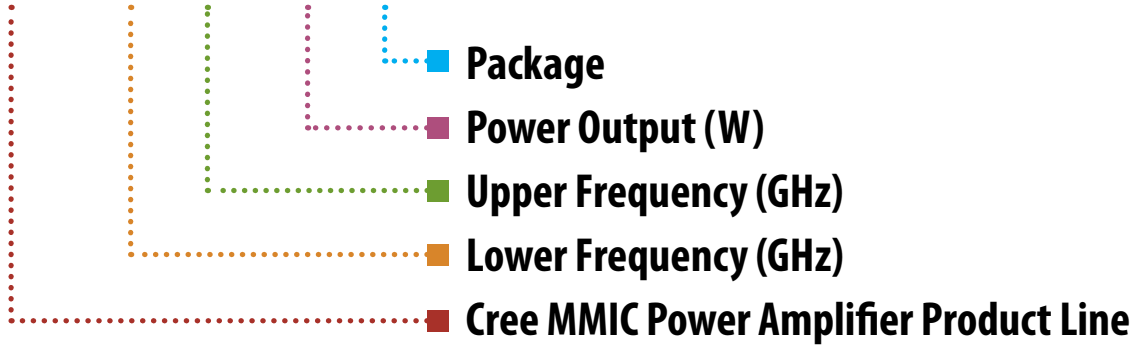
### Notes:

<sup>1</sup> The input, output and decoupling capacitors should be attached as close as possible to the die- typical distance is 5 to 10 mils with a maximum of 15 mils.

<sup>2</sup> The MMIC die and capacitors should be connected with 1 mil gold bond wires.

## Part Number System

# CMPA601C025D



Parameter	Value	Units
Lower Frequency	6.0	GHz
Upper Frequency <sup>1</sup>	12.0	GHz
Power Output	25	W
Package	Bare Die	-

**Table 1.**

**Note<sup>1</sup>:** Alpha characters used in frequency code indicate a value greater than 9.9 GHz. See Table 2 for value.

Character Code	Code Value
A	0
B	1
C	2
D	3
E	4
F	5
G	6
H	7
J	8
K	9
Examples:	1A = 10.0 GHz 2H = 27.0 GHz

**Table 2.**



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